

Notice of References Cited	Application/Control No. 10/517,860	Applicant(s)/Patent Under Reexamination ANNIC, ETIENNE	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0123423 A1	07-2003	Okanoue, Yasuyo	370/338
*	B	US-2003/0159109 A1	08-2003	Rossmann et al.	715/513
*	C	US-2003/0130008 A1	07-2003	Rajaniemi et al.	455/551
*	D	US-6,600,930 B1	07-2003	Sakurai et al.	455/414.3
*	E	US-2006/0168303 A1	07-2006	Oyama et al.	709/231
*	F	US-2003/0169725 A1	09-2003	Ahmavaara et al.	370/352
*	G	US-2005/0117591 A1	06-2005	Hurta et al.	370/401
*	H	US-2005/0271034 A1	12-2005	Asokan et al.	370/349
*	I	US-7,016,353 B2	03-2006	Proctor et al.	370/392
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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